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JNL = Journal or Magazine **CNF** = Conference **STD** = Standard**1 The intrinsic pseudo-MOSFET technique**

Ionescu, A.M.; Munteanu, D.; Chovet, A.; Rusu, A.; Steriu, D.;
 Semiconductor Conference, 1997. CAS '97 Proceedings., 1997
 International, Volume: 1, 7-11 Oct. 1997
 Pages:217 - 220 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(260 KB\)\]](#) **IEEE CNF****2 On-wafer W-band determination of the driving point impedance of a double slot antenna**

Thayne, I.G.; Edgar, D.L.; Elgaid, K.; Chong, H.; Jubber, M.; McLelland, H.; Ferguson, S.; Ross, A.; Arnold, J.M.; Heeres, R.; Whybourn, N.; Luinge, W.; V Der Vorst, M.; Neto, A.; De Maagt, P.;
 Microwave Measurements: Current Techniques and Trends (Ref. No. 1999/00
 IEE Colloquium on, 23 Feb. 1999
 Pages:3/1 - 3/4

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